Welcome to E-XFL.COM

What is "Embedded - Microcontrollers"?

"Embedded - Microcontrollers" refer to small, integrated circuits designed to perform specific tasks within larger systems. These microcontrollers are essentially compact computers on a single chip, containing a processor core, memory, and programmable input/output peripherals. They are called "embedded" because they are embedded within electronic devices to control various functions, rather than serving as standalone computers. Microcontrollers are crucial in modern electronics, providing the intelligence and control needed for a wide range of applications.

Applications of "Embedded - Microcontrollers"

Details	
Product Status	Obsolete
Core Processor	ARM7®
Core Size	16/32-Bit
Speed	60MHz
Connectivity	I²C, Microwire, SPI, SSI, SSP, UART/USART
Peripherals	Brown-out Detect/Reset, POR, PWM, WDT
Number of I/O	47
Program Memory Size	64KB (64K x 8)
Program Memory Type	FLASH
EEPROM Size	-
RAM Size	16K x 8
Voltage - Supply (Vcc/Vdd)	3V ~ 3.6V
Data Converters	A/D 8x10b; D/A 1x10b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 85°C (TA)
Mounting Type	Surface Mount
Package / Case	64-LQFP
Supplier Device Package	64-LQFP (10x10)
Purchase URL	https://www.e-xfl.com/product-detail/nxp-semiconductors/lpc2132fbd64-151

- One (LPC2131/32) or two (LPC2134/36/38) 8-channel 10-bit ADCs provide a total of up to 16 analog inputs, with conversion times as low as 2.44 μs per channel.
- Single 10-bit DAC provides variable analog output (LPC2132/34/36/38).
- Two 32-bit timers/external event counters (with four capture and four compare channels each), PWM unit (six outputs) and watchdog.
- Low power Real-time clock with independent power and dedicated 32 kHz clock input.
- Multiple serial interfaces including two UARTs (16C550), two Fast I^2C-bus (400 kbit/s), SPI and SSP with buffering and variable data length capabilities.
- Vectored interrupt controller with configurable priorities and vector addresses.
- Up to forty-seven 5 V tolerant general purpose I/O pins in tiny LQFP64 or HVQFN package.
- Up to nine edge or level sensitive external interrupt pins available.
- 60 MHz maximum CPU clock available from programmable on-chip PLL with settling time of 100 μs.
- On-chip integrated oscillator operates with external crystal in range of 1 MHz to 30 MHz and with external oscillator up to 50 MHz.
- Power saving modes include Idle and Power-down.
- Individual enable/disable of peripheral functions as well as peripheral clock scaling down for additional power optimization.
- Processor wake-up from Power-down mode via external interrupt or BOD.
- Single power supply chip with POR and BOD circuits:
  - CPU operating voltage range of 3.0 V to 3.6 V (3.3 V ± 10 %) with 5 V tolerant I/O pads.

3. Ordering information

Table 1. Ordering information

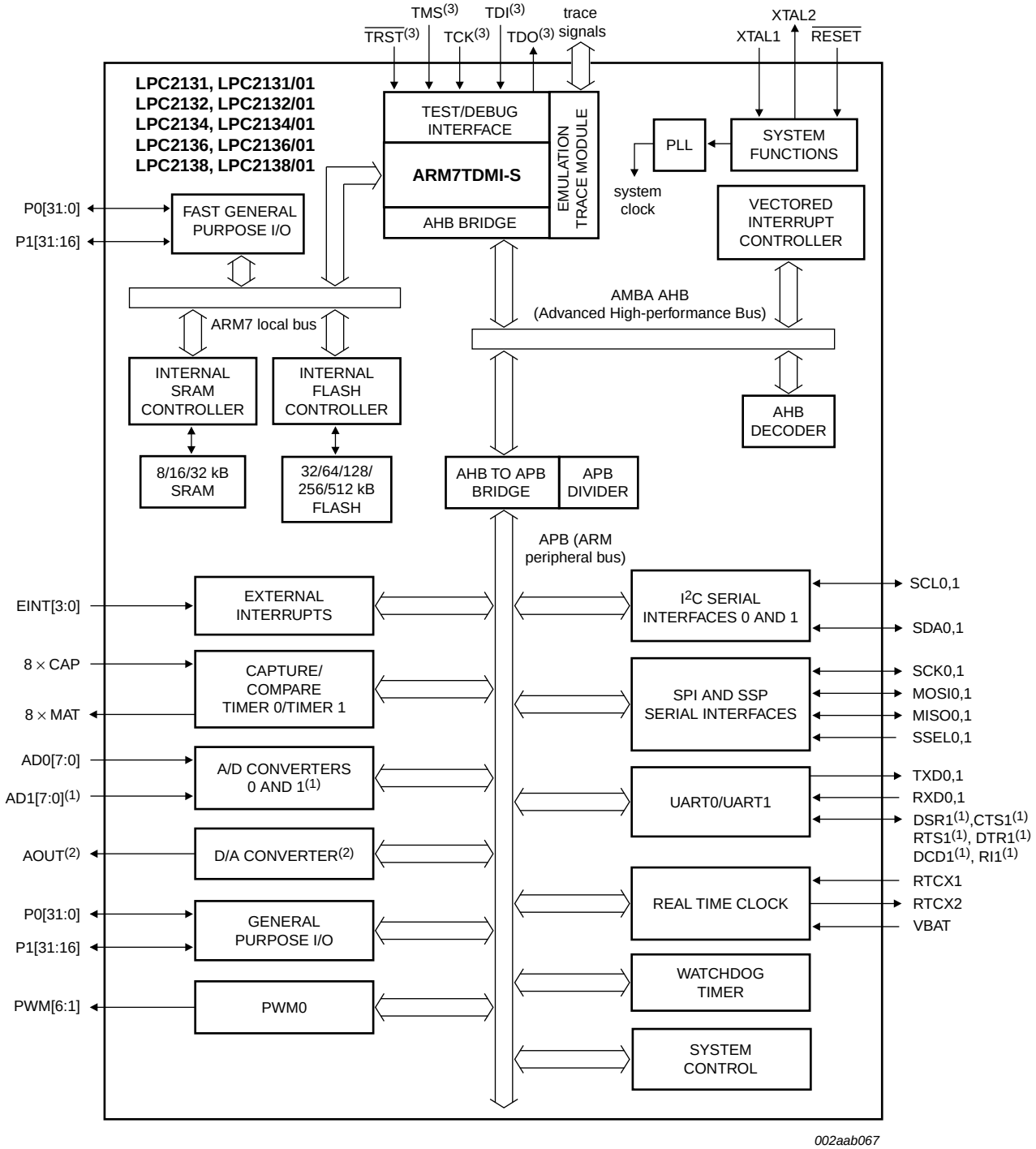
Type number	Package		
	Name	Description	Version
LPC2131FBD64/01	LQFP64	plastic low profile quad flat package; 64 leads; body 10 × 10 × 1.4 mm	SOT314-2
LPC2132FBD64/01	LQFP64	plastic low profile quad flat package; 64 leads; body 10 × 10 × 1.4 mm	SOT314-2
LPC2132FHN64/01	HVQFN64	plastic thermal enhanced very thin quad flat package; no leads; 64 terminals; body 9 × 9 × 0.85 mm	SOT804-2
LPC2134FBD64/01	LQFP64	plastic low profile quad flat package; 64 leads; body 10 × 10 × 1.4 mm	SOT314-2
LPC2136FBD64/01	LQFP64	plastic low profile quad flat package; 64 leads; body 10 × 10 × 1.4 mm	SOT314-2
LPC2138FBD64/01	LQFP64	plastic low profile quad flat package; 64 leads; body 10 × 10 × 1.4 mm	SOT314-2
LPC2138FHN64/01	HVQFN64	plastic thermal enhanced very thin quad flat package; no leads; 64 terminals; body 9 × 9 × 0.85 mm	SOT804-2

3.1 Ordering options

Table 2. Ordering options

Type number	Flash memory	RAM	ADC	DAC	Enhanced UARTs, ADC, Fast I/Os, and BOD	Temperature range
LPC2131FBD64/01	32 kB	8 kB	1	-	yes	−40 °C to +85 °C
LPC2132FBD64/01	64 kB	16 kB	1	1	yes	−40 °C to +85 °C
LPC2132FHN64/01	64 kB	16 kB	1	1	yes	−40 °C to +85 °C
LPC2134FBD64/01	128 kB	16 kB	2	1	yes	−40 °C to +85 °C
LPC2136FBD64/01	256 kB	32 kB	2	1	yes	−40 °C to +85 °C
LPC2138FBD64/01	512 kB	32 kB	2	1	yes	−40 °C to +85 °C
LPC2138FHN64/01	512 kB	32 kB	2	1	yes	−40 °C to +85 °C

4. Block diagram



(1) LPC2134/36/38 only.

(2) LPC2132/34/36/38 only.

(3) Pins shared with GPIO.

Fig 1. Block diagram

Table 3. Pin description *…continued*

Symbol	Pin	Type	Description
P1.26/RTCK	24[6]	I/O	**RTCK —** Returned Test Clock output. Extra signal added to the JTAG port. Assists debugger synchronization when processor frequency varies. Bidirectional pin with internal pull-up. LOW on RTCK while $\overline{\text{RESET}}$ is LOW enables pins P1.31:26 to operate as Debug port after reset.
P1.27/TDO	64[6]	O	**TDO —** Test Data out for JTAG interface.
P1.28/TDI	60[6]	I	**TDI —** Test Data in for JTAG interface.
P1.29/TCK	56[6]	I	**TCK —** Test Clock for JTAG interface.
P1.30/TMS	52[6]	I	**TMS —** Test Mode Select for JTAG interface.
P1.31/$\overline{\text{TRST}}$	20[6]	I	**$\overline{\text{TRST}}$ —** Test Reset for JTAG interface.
$\overline{\text{RESET}}$	57[7]	I	**External reset input:** A LOW on this pin resets the device, causing I/O ports and peripherals to take on their default states, and processor execution to begin at address 0. TTL with hysteresis, 5 V tolerant.
XTAL1	62[8]	I	Input to the oscillator circuit and internal clock generator circuits.
XTAL2	61[8]	O	Output from the oscillator amplifier.
RTCX1	3[9]	I	Input to the RTC oscillator circuit.
RTCX2	5[9]	O	Output from the RTC oscillator circuit.
V_{SS}	6, 18, 25, 42, 50	I	**Ground:** 0 V reference.
V_{SSA}	59	I	**Analog ground:** 0 V reference. This should nominally be the same voltage as V_{SS}, but should be isolated to minimize noise and error.
V_{DD}	23, 43, 51	I	**3.3 V power supply:** This is the power supply voltage for the core and I/O ports.
V_{DDA}	7	I	**Analog 3.3 V power supply:** This should be nominally the same voltage as V_{DD} but should be isolated to minimize noise and error. This voltage is used to power the on-chip PLL.
VREF	63	I	**ADC reference:** This should be nominally the same voltage as V_{DD} but should be isolated to minimize noise and error. Level on this pin is used as a reference for A/D and D/A convertor(s).
VBAT	49	I	**RTC power supply:** 3.3 V on this pin supplies the power to the RTC.

[1] 5 V tolerant pad providing digital I/O functions with TTL levels and hysteresis and 10 ns slew rate control.

[2] 5 V tolerant pad providing digital I/O functions with TTL levels and hysteresis and 10 ns slew rate control. If configured for an input function, this pad utilizes built-in glitch filter that blocks pulses shorter than 3 ns.

[3] Open drain 5 V tolerant digital I/O I^2C-bus 400 kHz specification compatible pad. It requires external pull-up to provide an output functionality.

[4] 5 V tolerant pad providing digital I/O (with TTL levels and hysteresis and 10 ns slew rate control) and analog input function. If configured for an input function, this pad utilizes built-in glitch filter that blocks pulses shorter than 3 ns. When configured as an ADC input, digital section of the pad is disabled.

[5] 5 V tolerant pad providing digital I/O (with TTL levels and hysteresis and 10 ns slew rate control) and analog output function. When configured as the DAC output, digital section of the pad is disabled.

[6] 5 V tolerant pad with built-in pull-up resistor providing digital I/O functions with TTL levels and hysteresis and 10 ns slew rate control. The pull-up resistor's value ranges from 60 kΩ to 300 kΩ.

[7] 5 V tolerant pad providing digital input (with TTL levels and hysteresis) function only.

[8] Pad provides special analog functionality.

[9] When unused, the RTCX1 pin can be grounded or left floating. For lowest power leave it floating.
The other RTC pin, RTCX2, should be left floating.

6. Functional description

6.1 Architectural overview

The ARM7TDMI-S is a general purpose 32-bit microprocessor, which offers high performance and very low power consumption. The ARM architecture is based on Reduced Instruction Set Computer (RISC) principles, and the instruction set and related decode mechanism are much simpler than those of microprogrammed Complex Instruction Set Computers. This simplicity results in a high instruction throughput and impressive real-time interrupt response from a small and cost-effective processor core.

Pipeline techniques are employed so that all parts of the processing and memory systems can operate continuously. Typically, while one instruction is being executed, its successor is being decoded, and a third instruction is being fetched from memory.

The ARM7TDMI-S processor also employs a unique architectural strategy known as Thumb, which makes it ideally suited to high-volume applications with memory restrictions, or applications where code density is an issue.

The key idea behind Thumb is that of a super-reduced instruction set. Essentially, the ARM7TDMI-S processor has two instruction sets:

- The standard 32-bit ARM set.
- A 16-bit Thumb set.

The Thumb set's 16-bit instruction length allows it to approach twice the density of standard ARM code while retaining most of the ARM's performance advantage over a traditional 16-bit processor using 16-bit registers. This is possible because Thumb code operates on the same 32-bit register set as ARM code.

Thumb code is able to provide up to 65 % of the code size of ARM, and 160 % of the performance of an equivalent ARM processor connected to a 16-bit memory system.

6.2 On-chip flash program memory

The LPC2131/32/34/36/38 incorporate a 32 kB, 64 kB, 128 kB, 256 kB and 512 kB flash memory system respectively. This memory may be used for both code and data storage. Programming of the flash memory may be accomplished in several ways. It may be programmed In System via the serial port. The application program may also erase and/or program the flash while the application is running, allowing a great degree of flexibility for data storage field firmware upgrades, etc. When the LPC2131/32/34/36/38 on-chip bootloader is used, 32/64/128/256/500 kB of flash memory is available for user code.

The LPC2131/32/34/36/38 flash memory provides a minimum of 100000 erase/write cycles and 20 years of data-retention.

6.3 On-chip static RAM

On-chip static RAM may be used for code and/or data storage. The SRAM may be accessed as 8-bit, 16-bit, and 32-bit. The LPC2131, LPC2132/34, and LPC2136/38 provide 8 kB, 16 kB and 32 kB of static RAM respectively.

6.5 Interrupt controller

The Vectored Interrupt Controller (VIC) accepts all of the interrupt request inputs and categorizes them as Fast Interrupt reQuest (FIQ), vectored Interrupt ReQuest (IRQ), and non-vectored IRQ as defined by programmable settings. The programmable assignment scheme means that priorities of interrupts from the various peripherals can be dynamically assigned and adjusted.

FIQ has the highest priority. If more than one request is assigned to FIQ, the VIC combines the requests to produce the FIQ signal to the ARM processor. The fastest possible FIQ latency is achieved when only one request is classified as FIQ, because then the FIQ service routine can simply start dealing with that device. But if more than one request is assigned to the FIQ class, the FIQ service routine can read a word from the VIC that identifies which FIQ source(s) is (are) requesting an interrupt.

Vectored IRQs have the middle priority. Sixteen of the interrupt requests can be assigned to this category. Any of the interrupt requests can be assigned to any of the 16 vectored IRQ slots, among which slot 0 has the highest priority and slot 15 has the lowest.

Non-vectored IRQs have the lowest priority.

The VIC combines the requests from all the vectored and non-vectored IRQs to produce the IRQ signal to the ARM processor. The IRQ service routine can start by reading a register from the VIC and jumping there. If any of the vectored IRQs are requesting, the VIC provides the address of the highest-priority requesting IRQs service routine, otherwise it provides the address of a default routine that is shared by all the non-vectored IRQs. The default routine can read another VIC register to see what IRQs are active.

6.5.1 Interrupt sources

Table 4 lists the interrupt sources for each peripheral function. Each peripheral device has one interrupt line connected to the Vectored Interrupt Controller, but may have several internal interrupt flags. Individual interrupt flags may also represent more than one interrupt source.

Table 4. Interrupt sources

Block	Flag(s)	VIC channel #
WDT	Watchdog Interrupt (WDINT)	0
-	Reserved for software interrupts only	1
ARM Core	EmbeddedICE, DbgCommRX	2
ARM Core	EmbeddedICE, DbgCommTX	3
TIMER0	Match 0 to 3 (MR0, MR1, MR2, MR3) Capture 0 to 3 (CR0, CR1, CR2, CR3)	4
TIMER1	Match 0 to 3 (MR0, MR1, MR2, MR3) Capture 0 to 3 (CR0, CR1, CR2, CR3)	5
UART0	RX Line Status (RLS) Transmit Holding Register empty (THRE) RX Data Available (RDA) Character Time-out Indicator (CTI)	6

6.17 Pulse width modulator

The PWM is based on the standard Timer block and inherits all of its features, although only the PWM function is pinned out on the LPC2131/32/34/36/38. The Timer is designed to count cycles of the peripheral clock (PCLK) and optionally generate interrupts or perform other actions when specified timer values occur, based on seven match registers. The PWM function is also based on match register events.

The ability to separately control rising and falling edge locations allows the PWM to be used for more applications. For instance, multi-phase motor control typically requires three non-overlapping PWM outputs with individual control of all three pulse widths and positions.

Two match registers can be used to provide a single edge controlled PWM output. One match register (MR0) controls the PWM cycle rate, by resetting the count upon match. The other match register controls the PWM edge position. Additional single edge controlled PWM outputs require only one match register each, since the repetition rate is the same for all PWM outputs. Multiple single edge controlled PWM outputs will all have a rising edge at the beginning of each PWM cycle, when an MR0 match occurs.

Three match registers can be used to provide a PWM output with both edges controlled. Again, the MR0 match register controls the PWM cycle rate. The other match registers control the two PWM edge positions. Additional double edge controlled PWM outputs require only two match registers each, since the repetition rate is the same for all PWM outputs.

With double edge controlled PWM outputs, specific match registers control the rising and falling edge of the output. This allows both positive going PWM pulses (when the rising edge occurs prior to the falling edge), and negative going PWM pulses (when the falling edge occurs prior to the rising edge).

6.17.1 Features

- Seven match registers allow up to six single edge controlled or three double edge controlled PWM outputs, or a mix of both types.
- The match registers also allow:
  - Continuous operation with optional interrupt generation on match.
  - Stop timer on match with optional interrupt generation.
  - Reset timer on match with optional interrupt generation.
- Supports single edge controlled and/or double edge controlled PWM outputs. Single edge controlled PWM outputs all go HIGH at the beginning of each cycle unless the output is a constant LOW. Double edge controlled PWM outputs can have either edge occur at any position within a cycle. This allows for both positive going and negative going pulses.
- Pulse period and width can be any number of timer counts. This allows complete flexibility in the trade-off between resolution and repetition rate. All PWM outputs will occur at the same repetition rate.
- Double edge controlled PWM outputs can be programmed to be either positive going or negative going pulses.

6.18.8 Power Control

The LPC2131/32/34/36/38 support two reduced power modes: Idle mode and Power-down mode.

In Idle mode, execution of instructions is suspended until either a reset or interrupt occurs. Peripheral functions continue operation during Idle mode and may generate interrupts to cause the processor to resume execution. Idle mode eliminates power used by the processor itself, memory systems and related controllers, and internal buses.

In Power-down mode, the oscillator is shut down and the chip receives no internal clocks. The processor state and registers, peripheral registers, and internal SRAM values are preserved throughout Power-down mode and the logic levels of chip output pins remain static. The Power-down mode can be terminated and normal operation resumed by either a reset or certain specific interrupts that are able to function without clocks. Since all dynamic operation of the chip is suspended, Power-down mode reduces chip power consumption to nearly zero.

Selecting an external 32 kHz clock instead of the PCLK as a clock-source for the on-chip RTC will enable the microcontroller to have the RTC active during Power-down mode. Power-down current is increased with RTC active. However, it is significantly lower than in Idle mode.

A Power Control for Peripherals feature allows individual peripherals to be turned off if they are not needed in the application, resulting in additional power savings.

6.18.9 APB bus

The APB divider determines the relationship between the processor clock (CCLK) and the clock used by peripheral devices (PCLK). The APB divider serves two purposes. The first is to provide peripherals with the desired PCLK via APB bus so that they can operate at the speed chosen for the ARM processor. In order to achieve this, the APB bus may be slowed down to $\frac{1}{2}$ to $\frac{1}{4}$ of the processor clock rate. Because the APB bus must work properly at power-up (and its timing cannot be altered if it does not work since the APB divider control registers reside on the APB bus), the default condition at reset is for the APB bus to run at $\frac{1}{4}$ of the processor clock rate. The second purpose of the APB divider is to allow power savings when an application does not require any peripherals to run at the full processor rate. Because the APB divider is connected to the PLL output, the PLL remains active (if it was running) during Idle mode.

6.19 Emulation and debugging

The LPC2131/32/34/36/38 support emulation and debugging via a JTAG serial port. A trace port allows tracing program execution. Debugging and trace functions are multiplexed only with GPIOs on Port 1. This means that all communication, timer and interface peripherals residing on Port 0 are available during the development and debugging phase as they are when the application is run in the embedded system itself.

6.19.1 EmbeddedICE

Standard ARM EmbeddedICE logic provides on-chip debug support. The debugging of the target system requires a host computer running the debugger software and an EmbeddedICE protocol convertor. EmbeddedICE protocol convertor converts the Remote Debug Protocol commands to the JTAG data needed to access the ARM core.

7. Limiting values

Table 5. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).[1]

Symbol	Parameter	Conditions		Min	Max	Unit
V_{DD}	supply voltage (core and external rail)			–0.5	+3.6	V
V_{DDA}	analog 3.3 V pad supply voltage			–0.5	+4.6	V
$V_{i(VBAT)}$	input voltage on pin VBAT	for the RTC		–0.5	+4.6	V
$V_{i(VREF)}$	input voltage on pin VREF			–0.5	+4.6	V
V_{IA}	analog input voltage	on ADC related pins		–0.5	+5.1	V
V_I	input voltage	5 V tolerant I/O pins; only valid when the V_{DD} supply voltage is present	[2]	–0.5	+6.0	V
		other I/O pins	[2][3]	–0.5	V_{DD} + 0.5	V
I_{DD}	supply current	per supply pin	[4]	-	100	mA
I_{SS}	ground current	per ground pin	[4]	-	100	mA
I_{sink}	sink current	for I^2C-bus; DC; T = 85 °C		-	20	mA
T_{stg}	storage temperature		[5]	–40	+125	°C
$P_{tot(pack)}$	total power dissipation (per package)	based on package heat transfer, not device power consumption		-	1.5	W
V_{ESD}	electrostatic discharge voltage	human body model	[6]			
		all pins		–4000	+4000	V

[1] The following applies to the Limiting values:

a) This product includes circuitry specifically designed for the protection of its internal devices from the damaging effects of excessive static charge. Nonetheless, it is suggested that conventional precautions be taken to avoid applying greater than the rated maximum.

b) Parameters are valid over operating temperature range unless otherwise specified. All voltages are with respect to V_{SS} unless otherwise noted.

[2] Including voltage on outputs in 3-state mode.

[3] Not to exceed 4.6 V.

[4] The peak current is limited to 25 times the corresponding maximum current.

[5] Dependent on package type.

[6] Human body model: equivalent to discharging a 100 pF capacitor through a 1.5 kΩ series resistor.

8. Static characteristics

Table 6. Static characteristics

T_{amb} = −40 °C to +85 °C for commercial applications, unless otherwise specified.

Symbol	Parameter	Conditions		Min	Typ[1]	Max	Unit
V_{DD}	supply voltage (core and external rail)			3.0	3.3	3.6	V
V_{DDA}	analog 3.3 V pad supply voltage			2.5	3.3	3.6	V
$V_{i(VBAT)}$	input voltage on pin VBAT		[2]	2.0	3.3	3.6	V
$V_{i(VREF)}$	input voltage on pin VREF			2.5	3.3	3.6	V
Standard port pins, $\overline{\text{RESET}}$, P1.26/RTCK							
I_{IL}	LOW-level input current	V_I = 0 V; no pull-up		-	-	3	μA
I_{IH}	HIGH-level input current	$V_I = V_{DD}$; no-pull-down		-	-	3	μA
I_{OZ}	OFF-state output current	V_O = 0 V; $V_O = V_{DD}$; no pull-up/down		-	-	3	μA
I_{latch}	I/O latch-up current	$-(0.5V_{DD}) < V_I < (1.5V_{DD})$; T_j < 125 °C		-	-	100	mA
V_I	input voltage	pin configured to provide a digital function	[3][4][5] [6]	0	-	5.5	V
V_O	output voltage	output active		0	-	V_{DD}	V
V_{IH}	HIGH-level input voltage			2.0	-	-	V
V_{IL}	LOW-level input voltage			-	-	0.8	V
V_{hys}	hysteresis voltage			0.4	-	-	V
V_{OH}	HIGH-level output voltage	I_{OH} = −4 mA	[7]	V_{DD} − 0.4	-	-	V
V_{OL}	LOW-level output voltage	I_{OL} = −4 mA	[7]	-	-	0.4	V
I_{OH}	HIGH-level output current	$V_{OH} = V_{DD}$ − 0.4 V	[7]	−4	-	-	mA
I_{OL}	LOW-level output current	V_{OL} = 0.4 V	[7]	4	-	-	mA
I_{OHS}	HIGH-level short-circuit output current	V_{OH} = 0 V	[8]	-	-	−45	mA
I_{OLS}	LOW-level short-circuit output current	$V_{OL} = V_{DDA}$	[8]	-	-	50	mA
I_{pd}	pull-down current	V_I = 5 V	[9]	10	50	150	μA
I_{pu}	pull-up current	V_I = 0 V	[10]	−15	−50	−85	μA
		$V_{DD} < V_I$ < 5 V	[9]	0	0	0	μA
$I_{DD(act)}$	active mode supply current	V_{DD} = 3.3 V; T_{amb} = 25 °C; code `while(1){}` executed from flash, no active peripherals					
		CCLK = 10 MHz		-	10	-	mA
		CCLK = 60 MHz		-	40	-	mA
$I_{DD(pd)}$	Power-down mode supply current	V_{DD} = 3.3 V; T_{amb} = 25 °C		-	60	-	μA
		V_{DD} = 3.3 V; T_{amb} = 85 °C		-	200	500	μA

[4] V_{DD} supply voltages must be present.

[5] 3-state outputs go into 3-state mode when V_{DD} is grounded.

[6] Please also see the errata note mentioned in the errata sheet.

[7] Accounts for 100 mV voltage drop in all supply lines.

[8] Only allowed for a short time period.

[9] Minimum condition for V_I = 4.5 V, maximum condition for V_I = 5.5 V.

[10] Applies to P1.16 to P1.25.

[11] On pin VBAT.

[12] Optimized for low battery consumption.

[13] To V_{SS}.

9. Dynamic characteristics

Table 7. Dynamic characteristics

T_{amb} = −40 °C to +85 °C for commercial applications, V_{DD} over specified ranges.[1]

Symbol	Parameter	Conditions	Min	Typ[2]	Max	Unit
External clock						
f_{osc}	oscillator frequency		10	-	25	MHz
$T_{cy(clk)}$	clock cycle time		40	-	100	ns
t_{CHCX}	clock HIGH time		$T_{cy(clk)} \times 0.4$	-	-	ns
t_{CLCX}	clock LOW time		$T_{cy(clk)} \times 0.4$	-	-	ns
t_{CLCH}	clock rise time		-	-	5	ns
t_{CHCL}	clock fall time		-	-	5	ns
Port pins (except P0.2 and P0.3)						
$t_{r(o)}$	output rise time		-	10	-	ns
$t_{f(o)}$	output fall time		-	10	-	ns
I^2C-bus pins (P0.2 and P0.3)						
$t_{f(o)}$	output fall time	V_{IH} to V_{IL}	$20 + 0.1 \times C_b$[3]	-	-	ns

[1] Parameters are valid over operating temperature range unless otherwise specified.

[2] Typical ratings are not guaranteed. The values listed are at room temperature (25 °C), nominal supply voltages.

[3] Bus capacitance C_b in pF, from 10 pF to 400 pF.

9.1 Timing

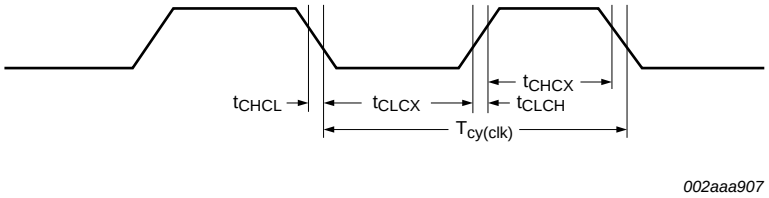
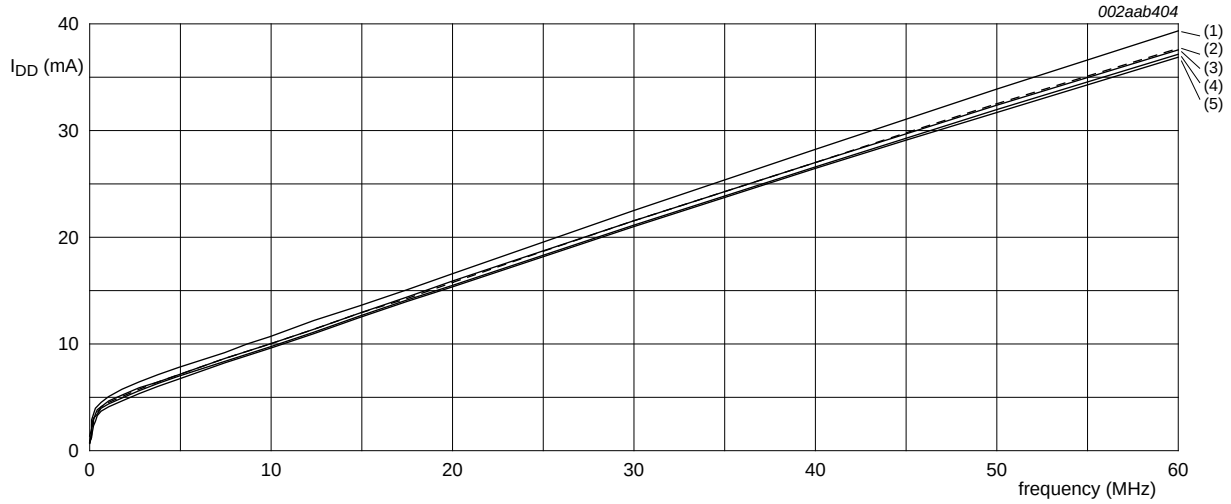


Fig 7. External clock timing (with an amplitude of at least $V_{i(RMS)}$ = 200 mV)

9.2 LPC2138 power consumption measurements



Test conditions: code executed from flash; all peripherals are enabled in PCONP register; PCLK = CCLK/4.

(1) V_{DD} = 3.6 V at −60 °C (max)

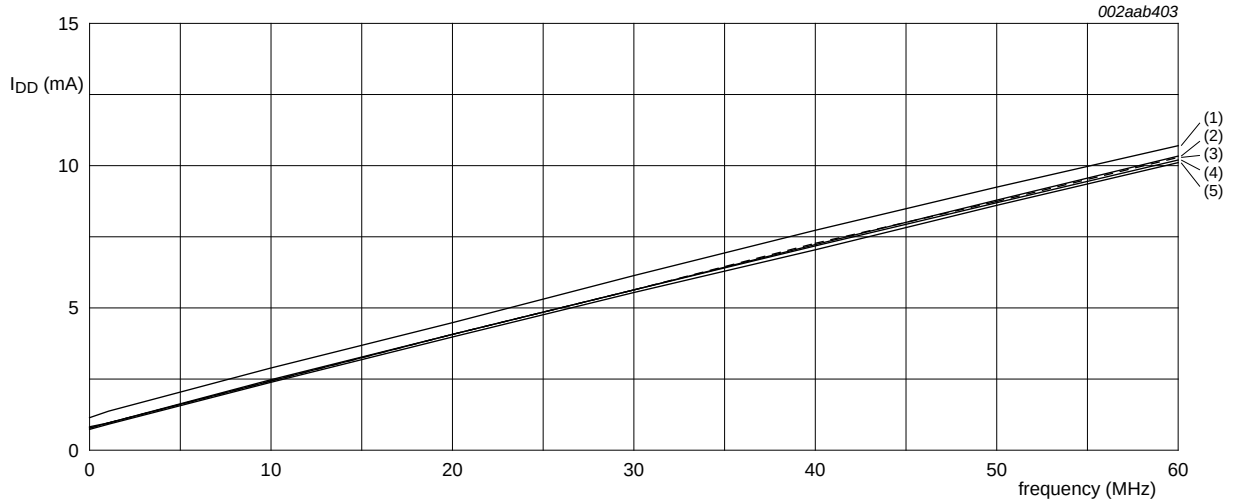
(2) V_{DD} = 3.6 V at 140 °C

(3) V_{DD} = 3.6 V at 25 °C

(4) V_{DD} = 3.3 V at 25 °C (typical)

(5) V_{DD} = 3.3 V at 95 °C (typical)

Fig 8. $I_{DD(act)}$ measured at different frequencies (CCLK) and temperatures



Test conditions: Idle mode entered executing code from flash; all peripherals are enabled in PCONP register; PCLK = CCLK/4.

(1) V_{DD} = 3.6 V at 140 °C (max)

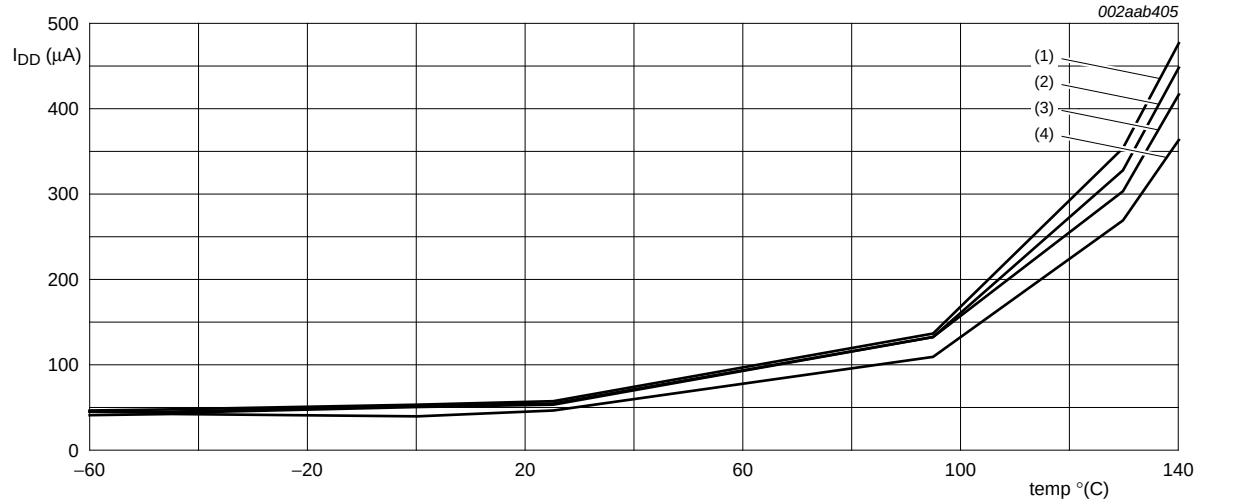
(2) V_{DD} = 3.6 V at −60 °C

(3) V_{DD} = 3.6 V at 25 °C

(4) V_{DD} = 3.3 V at 25 °C (typical)

(5) V_{DD} = 3.3 V at 95 °C (typical)

Fig 9. I_{DD} idle measured at different frequencies (CCLK) and temperatures



Test conditions: Power-down mode entered executing code from flash; all peripherals are enabled in PCONP register.

(1) V_{DD} = 3.6 V

(2) V_{DD} = 3.3 V (max)

(3) V_{DD} = 3.0 V

(4) V_{DD} = 3.3 V (typical)

Fig 10. $I_{DD(pd)}$ measured at different temperatures

10. ADC electrical characteristics

Table 8. ADC static characteristics

V_{DDA} = 2.5 V to 3.6 V; T_{amb} = –40 °C to +85 °C unless otherwise specified; ADC frequency 4.5 MHz.

Symbol	Parameter	Conditions		Min	Typ	Max	Unit
V_{IA}	analog input voltage			0	-	V_{DDA}	V
C_{ia}	analog input capacitance			-	-	1	pF
E_D	differential linearity error		[1][2][3]	-	-	±1	LSB
$E_{L(adj)}$	integral non-linearity		[1][4]	-	-	±2	LSB
E_O	offset error		[1][5]	-	-	±3	LSB
E_G	gain error		[1][6]	-	-	±0.5	%
E_T	absolute error		[1][7]	-	-	±4	LSB
R_{vsi}	voltage source interface resistance		[8]	-	-	40	kΩ

[1] Conditions: V_{SSA} = 0 V, V_{DDA} = 3.3 V.

[2] The ADC is monotonic, there are no missing codes.

[3] The differential linearity error (E_D) is the difference between the actual step width and the ideal step width. See Figure 11.

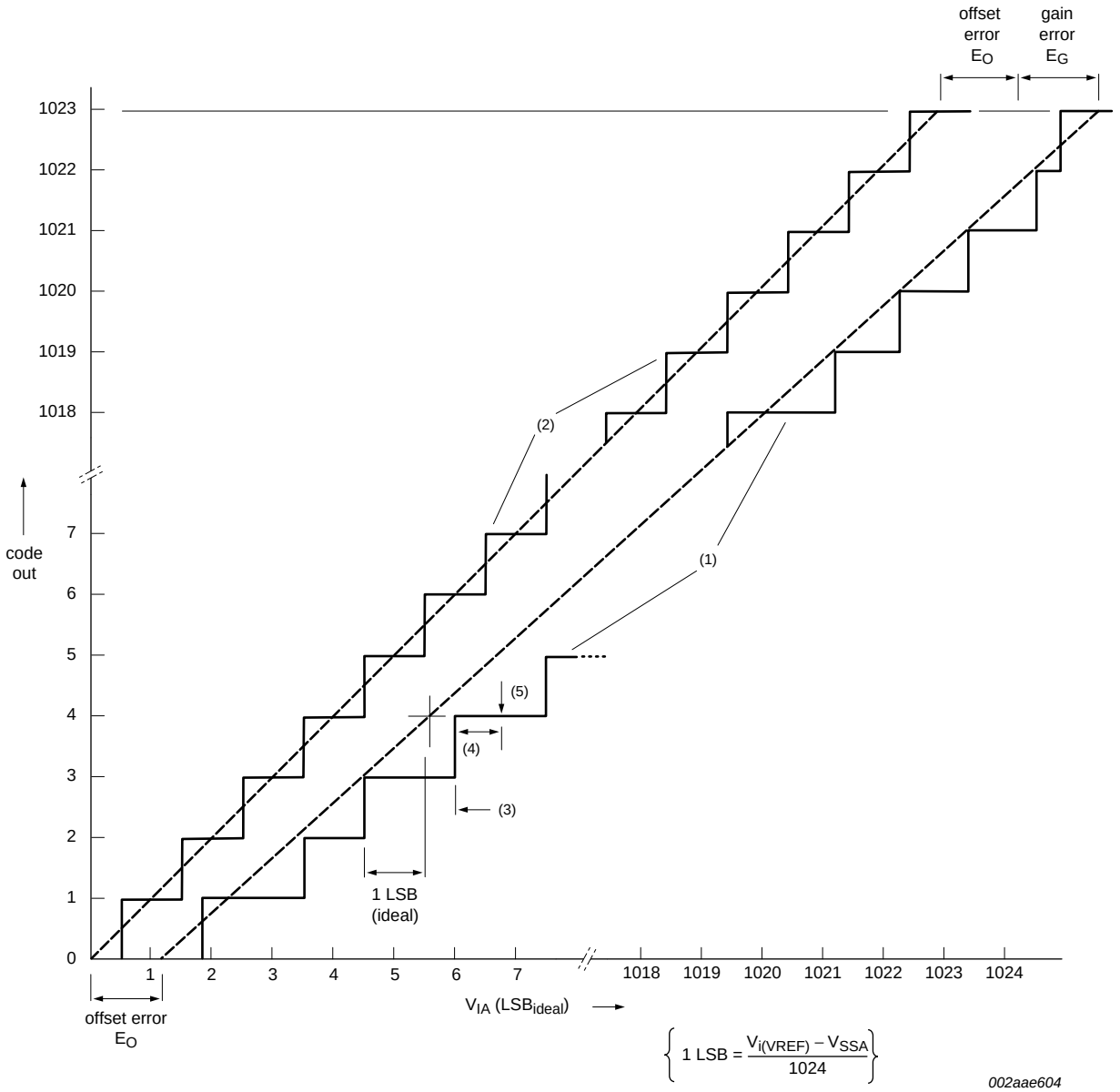
[4] The integral non-linearity ($E_{L(adj)}$) is the peak difference between the center of the steps of the actual and the ideal transfer curve after appropriate adjustment of gain and offset errors. See Figure 11.

[5] The offset error (E_O) is the absolute difference between the straight line which fits the actual curve and the straight line which fits the ideal curve. See Figure 11.

[6] The gain error (E_G) is the relative difference in percent between the straight line fitting the actual transfer curve after removing offset error, and the straight line which fits the ideal transfer curve. See Figure 11.

[7] The absolute error (E_T) is the maximum difference between the center of the steps of the actual transfer curve of the non-calibrated ADC and the ideal transfer curve. See Figure 11.

[8] See Figure 11.



(1) Example of an actual transfer curve.

(2) The ideal transfer curve.

(3) Differential linearity error (E_D).

(4) Integral non-linearity ($E_{L(adj)}$).

(5) Center of a step of the actual transfer curve.

Fig 11. ADC characteristics

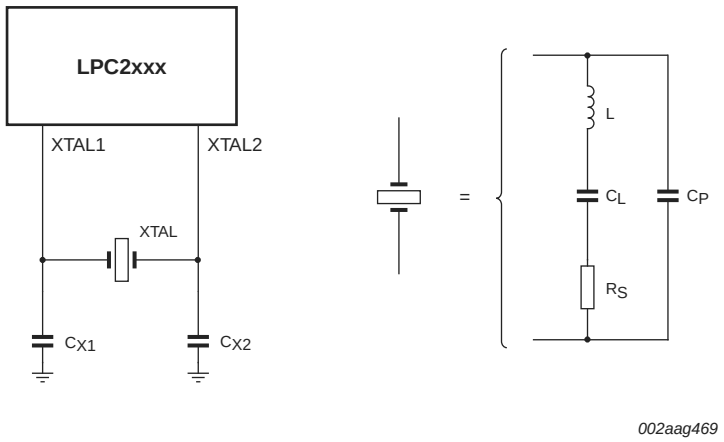


Fig 14. Oscillator modes and models: oscillation mode of operation and external crystal model used for C_{X1}/C_{X2} evaluation

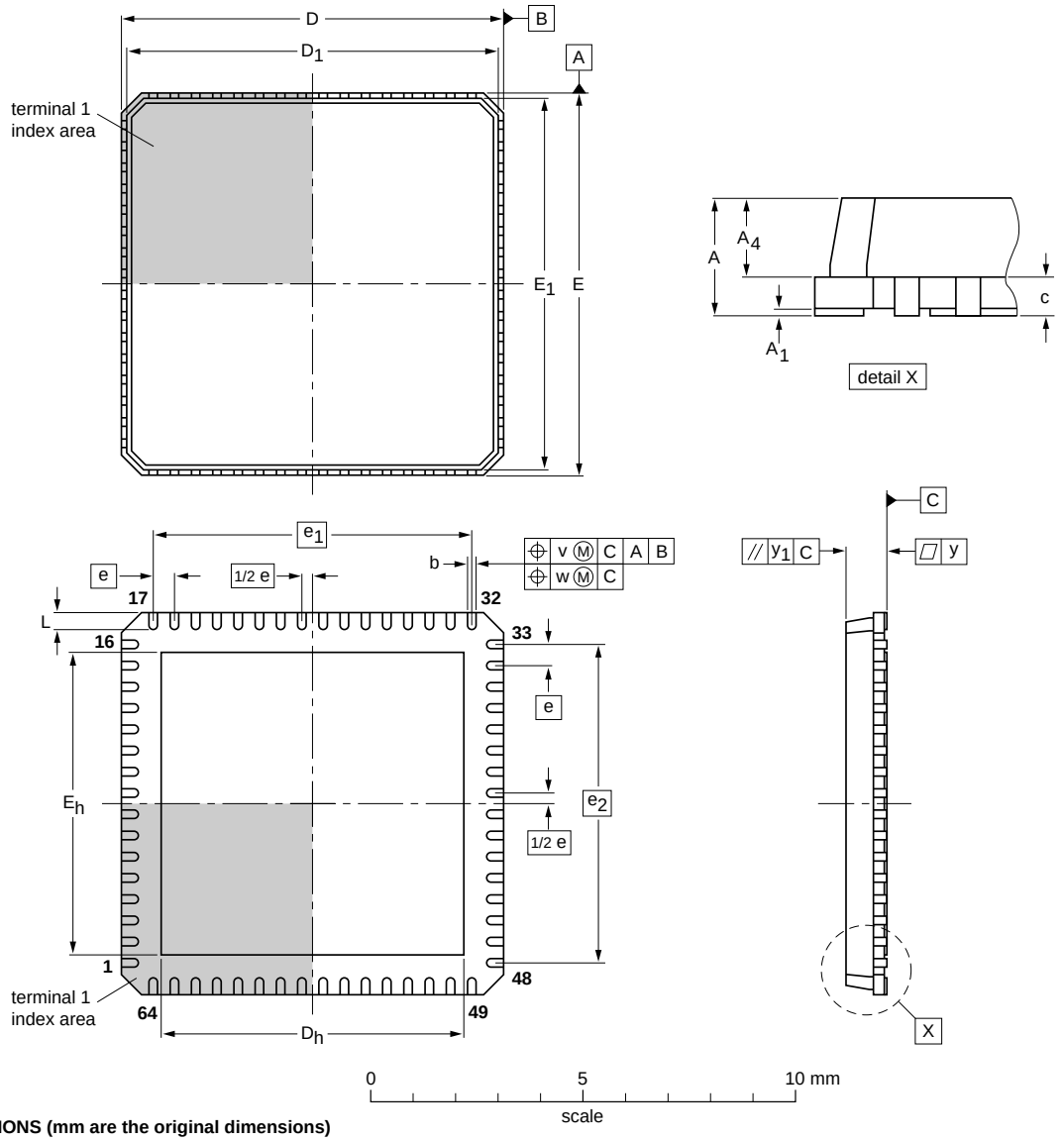
Table 10. Recommended values for C_{X1}/C_{X2} in oscillation mode (crystal and external components parameters): low frequency mode

Fundamental oscillation frequency F_{OSC}	Crystal load capacitance C_L	Maximum crystal series resistance R_S	External load capacitors C_{X1}/C_{X2}
1 MHz to 5 MHz	10 pF	< 300 Ω	18 pF, 18 pF
	20 pF	< 300 Ω	39 pF, 39 pF
	30 pF	< 300 Ω	57 pF, 57 pF
5 MHz to 10 MHz	10 pF	< 300 Ω	18 pF, 18 pF
	20 pF	< 200 Ω	39 pF, 39 pF
	30 pF	< 100 Ω	57 pF, 57 pF
10 MHz to 15 MHz	10 pF	< 160 Ω	18 pF, 18 pF
	20 pF	< 60 Ω	39 pF, 39 pF
15 MHz to 20 MHz	10 pF	< 80 Ω	18 pF, 18 pF

Table 11. Recommended values for C_{X1}/C_{X2} in oscillation mode (crystal and external components parameters): high frequency mode

Fundamental oscillation frequency F_{OSC}	Crystal load capacitance C_L	Maximum crystal series resistance R_S	External load capacitors C_{X1}, C_{X2}
15 MHz to 20 MHz	10 pF	< 180 Ω	18 pF, 18 pF
	20 pF	< 100 Ω	39 pF, 39 pF
20 MHz to 25 MHz	10 pF	< 160 Ω	18 pF, 18 pF
	20 pF	< 80 Ω	39 pF, 39 pF

HVQFN64: plastic thermal enhanced very thin quad flat package; no leads; 64 terminals; body 9 x 9 x 0.85 mm **SOT804-2**



DIMENSIONS (mm are the original dimensions)

UNIT	A max.	A_1	A_4	b	c	D	D_1	D_h	E	E_1	E_h	e	e_1	e_2	L	v	w	y	y_1
mm	1	0.05 0.00	0.80 0.65	0.30 0.18	0.2	9.05 8.95	8.95 8.55	7.25 6.95	9.05 8.95	8.95 8.55	7.25 6.95	0.5	7.5	7.5	0.5 0.3	0.1	0.05	0.05	0.1

OUTLINE VERSION	REFERENCES				EUROPEAN PROJECTION	ISSUE DATE
	IEC	JEDEC	JEITA			
SOT804-2	- - -	MO-220	- - -			04-03-25

Fig 17. Package outline SOT804-2 (HVQFN64)

16. Legal information

16.1 Data sheet status

Document status[1][2]	Product status[3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

[1] Please consult the most recently issued document before initiating or completing a design.

[2] The term 'short data sheet' is explained in section "Definitions".

[3] The product status of device(s) described in this document may have changed since this document was published and may differ in case of multiple devices. The latest product status information is available on the Internet at URL http://www.nxp.com.

16.2 Definitions

Draft — The document is a draft version only. The content is still under internal review and subject to formal approval, which may result in modifications or additions. NXP Semiconductors does not give any representations or warranties as to the accuracy or completeness of information included herein and shall have no liability for the consequences of use of such information.

Short data sheet — A short data sheet is an extract from a full data sheet with the same product type number(s) and title. A short data sheet is intended for quick reference only and should not be relied upon to contain detailed and full information. For detailed and full information see the relevant full data sheet, which is available on request via the local NXP Semiconductors sales office. In case of any inconsistency or conflict with the short data sheet, the full data sheet shall prevail.

Product specification — The information and data provided in a Product data sheet shall define the specification of the product as agreed between NXP Semiconductors and its customer, unless NXP Semiconductors and customer have explicitly agreed otherwise in writing. In no event however, shall an agreement be valid in which the NXP Semiconductors product is deemed to offer functions and qualities beyond those described in the Product data sheet.

16.3 Disclaimers

Limited warranty and liability — Information in this document is believed to be accurate and reliable. However, NXP Semiconductors does not give any representations or warranties, expressed or implied, as to the accuracy or completeness of such information and shall have no liability for the consequences of use of such information.

In no event shall NXP Semiconductors be liable for any indirect, incidental, punitive, special or consequential damages (including - without limitation - lost profits, lost savings, business interruption, costs related to the removal or replacement of any products or rework charges) whether or not such damages are based on tort (including negligence), warranty, breach of contract or any other legal theory.

Notwithstanding any damages that customer might incur for any reason whatsoever, NXP Semiconductors' aggregate and cumulative liability towards customer for the products described herein shall be limited in accordance with the *Terms and conditions of commercial sale* of NXP Semiconductors.

Right to make changes — NXP Semiconductors reserves the right to make changes to information published in this document, including without limitation specifications and product descriptions, at any time and without notice. This document supersedes and replaces all information supplied prior to the publication hereof.

Suitability for use — NXP Semiconductors products are not designed, authorized or warranted to be suitable for use in life support, life-critical or safety-critical systems or equipment, nor in applications where failure or malfunction of an NXP Semiconductors product can reasonably be expected to result in personal injury, death or severe property or environmental damage. NXP Semiconductors accepts no liability for inclusion and/or use of NXP Semiconductors products in such equipment or applications and therefore such inclusion and/or use is at the customer's own risk.

Applications — Applications that are described herein for any of these products are for illustrative purposes only. NXP Semiconductors makes no representation or warranty that such applications will be suitable for the specified use without further testing or modification.

Customers are responsible for the design and operation of their applications and products using NXP Semiconductors products, and NXP Semiconductors accepts no liability for any assistance with applications or customer product design. It is customer's sole responsibility to determine whether the NXP Semiconductors product is suitable and fit for the customer's applications and products planned, as well as for the planned application and use of customer's third party customer(s). Customers should provide appropriate design and operating safeguards to minimize the risks associated with their applications and products.

NXP Semiconductors does not accept any liability related to any default, damage, costs or problem which is based on any weakness or default in the customer's applications or products, or the application or use by customer's third party customer(s). Customer is responsible for doing all necessary testing for the customer's applications and products using NXP Semiconductors products in order to avoid a default of the applications and the products or of the application or use by customer's third party customer(s). NXP does not accept any liability in this respect.

Limiting values — Stress above one or more limiting values (as defined in the Absolute Maximum Ratings System of IEC 60134) will cause permanent damage to the device. Limiting values are stress ratings only and (proper) operation of the device at these or any other conditions above those given in the Recommended operating conditions section (if present) or the Characteristics sections of this document is not warranted. Constant or repeated exposure to limiting values will permanently and irreversibly affect the quality and reliability of the device.

Terms and conditions of commercial sale — NXP Semiconductors products are sold subject to the general terms and conditions of commercial sale, as published at http://www.nxp.com/profile/terms, unless otherwise agreed in a valid written individual agreement. In case an individual agreement is concluded only the terms and conditions of the respective agreement shall apply. NXP Semiconductors hereby expressly objects to applying the customer's general terms and conditions with regard to the purchase of NXP Semiconductors products by customer.

No offer to sell or license — Nothing in this document may be interpreted or construed as an offer to sell products that is open for acceptance or the grant, conveyance or implication of any license under any copyrights, patents or other industrial or intellectual property rights.

Export control — This document as well as the item(s) described herein may be subject to export control regulations. Export might require a prior authorization from national authorities.

Non-automotive qualified products — Unless this data sheet expressly states that this specific NXP Semiconductors product is automotive qualified, the product is not suitable for automotive use. It is neither qualified nor tested in accordance with automotive testing or application requirements. NXP Semiconductors accepts no liability for inclusion and/or use of non-automotive qualified products in automotive equipment or applications.

In the event that customer uses the product for design-in and use in automotive applications to automotive specifications and standards, customer (a) shall use the product without NXP Semiconductors' warranty of the product for such automotive applications, use and specifications, and (b) whenever customer uses the product for automotive applications beyond NXP Semiconductors' specifications such use shall be solely at customer's own risk, and (c) customer fully indemnifies NXP Semiconductors for any liability, damages or failed product claims resulting from customer design and use of the product for automotive applications beyond NXP Semiconductors' standard warranty and NXP Semiconductors' product specifications.

16.4 Trademarks

Notice: All referenced brands, product names, service names and trademarks are the property of their respective owners.

I^2C-bus — logo is a trademark of NXP B.V.

17. Contact information

For more information, please visit: **http://www.nxp.com**

For sales office addresses, please send an email to: **salesaddresses@nxp.com**

18. Contents

For more information, please visit: http://www.nxp.com
For sales office addresses, please send an email to: salesaddresses@nxp.com

Date of release: 29 July 2011
Document identifier: LPC2131_32_34_36_38